

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-3513		PRIORITY SERIAL NO. 10447354		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Cem Basceri et al.				
				PRIORITY FILING DATE May 21, 2003		PRIORITY GROUP 313		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MD	AA	5,292,673	03-1994	Shinriki et al.				
MD	AB	5,486,488	01-1996	Kamiyama				
MD	AC	5,641,702	06-1997	Imai et al.				
MD	AD	5,726,083	03-1998	Takaishi				
MD	AE	5,893,734	04-1999	Jeng et al.				
MD	AF	6,117,725	09-2000	Huang				
MD	AG	6,200,893	03-2001	Sneh				
MD	AH	6,235,572	05-2001	Kunitomo et al.				
MD	AI	6,399,438	06-2002	Saito et al.				
MD	AJ	6,511,896	1/28/03	Basceri et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AK							
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
MD	AM		Bin Yu, et al., "70nm MOSFET with Ultra-Shallow, Abrupt, and Super-Doped S/D Extension Implemented by Laser Thermal Process (LTP)", IEEE, 03/1999.					
MD	AN		Somit Talwar, et al., "Ultra-Shallow, Abrupt, and Highly-Activated Junctions by Low-Energy Ion Implantation and Laser Annealing", Verdant Technologies, San Jose, CA.					
MD	AO		Ken-ichi Goto, et al., "Ultra-Low Contact Resistance for Deca-nm MOSFETs by Laser Annealing", IEEE, 09/1999, pps. 20.7.1-20.7.3.					
EXAMINER Renee Kley				DATE CONSIDERED 11-1-04				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

EW 372458410

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2515		SERIAL NO. 10/810,779	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Cem Basceri et al.			
					FILING DATE March 25, 2004		GROUP 2818	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
LAB	AA	4,450,041	03/84	Alduff	—	—	—	
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Portlant Pages, Etc.)								
	AR							
	AS							
EXAMINER <i>LAB</i>		DATE CONSIDERED <i>10-1-04</i>						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 600; Draw line through citation if not in conformance and not considered. Include copy of this form with read communication to applicant.								